HX510200V

Description

The HX510200V is a 200-watt, highly rugged, unmatched LDMOS FET, designed for wide-band commercial and industrial applications at frequencies HF to 800MHz.

•Typical Performance (On fixture with device soldered):

CW , VDS=48V, VGS=3.3V, Idq=200mA

Freq(MHz)	Pin(dBm)	Pout(dBm)	IDS(A)	Gain(dB)	EFF(%)
410	36.3	53.1	7.4	16.8	57.5%
420	36.1	53.3	7.6	17.2	58.6%
440	36	53.5	7.7	17.5	60.6%
460	36.2	53.5	7.8	17.3	59.8%
480	36.2	53.8	8.4	17.6	59.5%
500	36.5	53.9	8.9	17.4	57.5%
520	36.8	54	9.3	17.2	56.3%
540	35.8	53.9	9.1	18.1	56.2%
560	34.9	53.7	8.4	18.8	58.1%
580	35	53.5	7.9	18.5	59.0%
600	36	53	6.9	17	60.2%

Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift
- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant

Suitable Applications

- 2-30MHz (HF or Short wave communication)
- 30-88MHz (Ground communication)
- 54-88MHz (TV VHF I)
- 88-108MHz (FM)
- 118 -140MHz (Avionics)
- 136-174MHz (Commercial ground communication)
- 160-230MHz (TV VHF III)
- 30-512MHz (Jammer, Ground/Air communication)
- 470-860MHz (TV UHF)
- 100kHz - 1000MHz (ISM, instrumentation)

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain--Source Voltage	V_{DSS}	120	Vdc
Gate--Source Voltage	V_{GS}	-10 to +10	Vdc
Operating Voltage	V_{DD}	+55	Vdc
Storage Temperature Range	Tstg	-65 to +150	°C
Case Operating Temperature	T_C	+150	°C
Operating Junction Temperature	T_J	+225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case T_C= 85°C, T_J=200°C, DC test	$R_{\theta JC}$	0.58	°C/W

Table 3. ESD Protection Characteristics

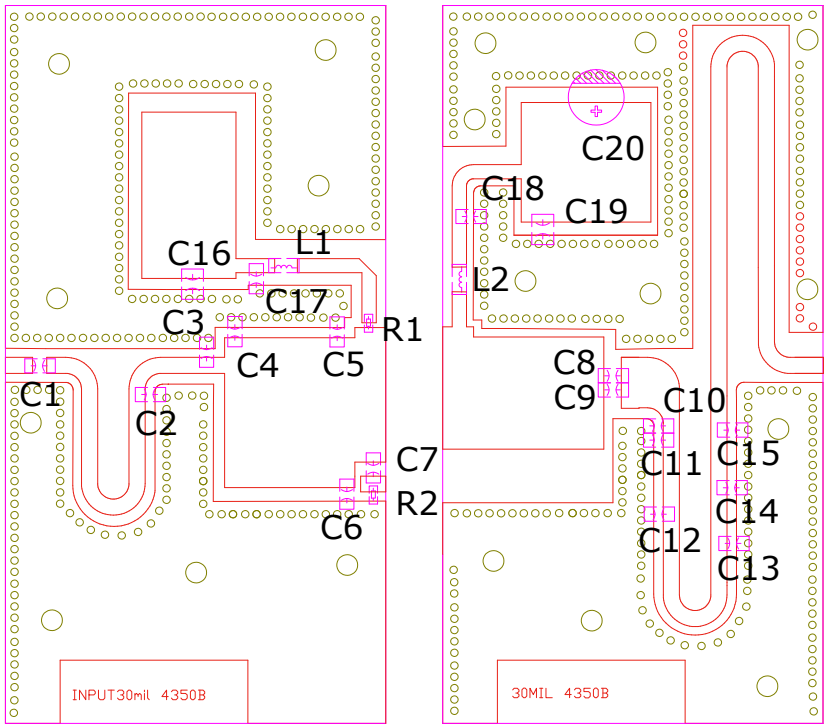
Test Methodology	Class
Human Body Model (per JESD22--A114)	Class 2

Table 4. Electrical Characteristics (TA = 25 ℃ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
DC Characteristics					
Drain-Source Voltage V_{GS}=0, I_{DS}=1.0mA	$V_{(BR)DSS}$		122		V
Zero Gate Voltage Drain Leakage Current (V_{DS} = 50V, V_{GS} = 0 V)	I_{DSS}	——	——	1	μA
Gate--Source Leakage Current (V_{GS} = 10 V, V_{DS} = 0 V)	I_{GSS}	——	——	1	μA
Gate Threshold Voltage (V_{DS} = 50V, I_D = 600 μA)	$V_{GS(th)}$	——	2.73	——	V
Gate Quiescent Voltage (V_{DD} = 50 V, I_D = 200 mA, Measured in Functional Test)	$V_{GS(Q)}$	——	3.3	——	V
Common Source Input Capacitance (V_{GS} = 0V, V_{DS} =50 V, f = 1 MHz)	C_{ISS}		150		pF
Common Source Output Capacitance (V_{GS} = 0V, V_{DS} =50 V, f = 1 MHz)	C_{OSS}		56		pF
Common Source Feedback Capacitance (V_{GS} = 0V, V_{DS} =50 V, f = 1 MHz)	C_{RSS}		1.6		pF
Functional Tests (In Demo Test Fixture, 50 ohm system) V_{DD} = 48 Vdc, I_{DQ} = 100mA, f = 600 MHz, CW Signal Measurements, Pin=36dBm					
Power Gain@Pout	Gp	——	17	——	dB
Output Power	Pout	30	200		W
Drain Efficiency@Pout	η_D	——	60	——	%
Input Return Loss	IRL	——	-7	——	dB

Reference Circuit of Test Fixture Assembly Diagram

410-600MHz Class AB

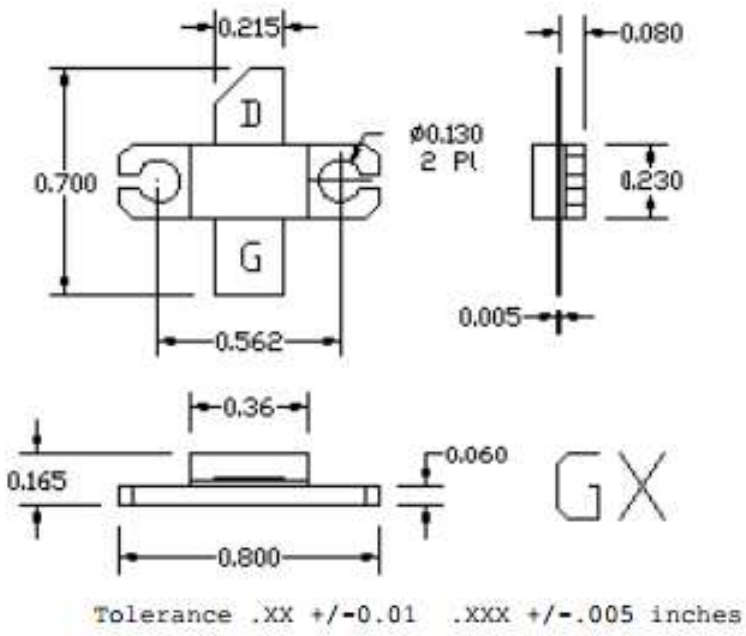


Test Circuit Component Designations and Values

Component	Description	Suggested Manufacturer
C1	100pF	ATC600F
C2	15pF	ATC800B
C3	6.8pF	ATC800B
C4	20pF	ATC800B
C5, C6, C10	24pF	ATC800B
C8, C9, C17, C18	56pF	ATC600F
C11	8.2pF	ATC800B
C12	18pF	ATC800B
C13, C14	4.7pF	ATC800B
C15	3.3pF	ATC800B
C7, C16, C19	10uF 100V	Ceramic multilayer capacitor
C20	470uF,63V	Electrolytic Capacitor
R1, R2	9.1Ω， 1206	Chip Resistor
L1, L2	10nH	DIY air core inductance
PCB	0.762mm [0.030"] thick, εr=3.50, Rogers 4350B, 1 oz. copper	

Package Outline

Flanged ceramic package; 2 leads



OUTLINE VERSION	REFERENCE			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
PKG-G2E					03/12/2013

Figure 1. Package Outline PKG-G2E